



THE AMERICAN ASSOCIATION FOR
LABORATORY ACCREDITATION

ACCREDITED LABORATORY

A2LA has accredited

DELPHI-DELCO MTC LAB
Juarez, Chihuahua, Mexico

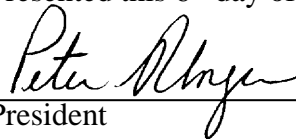
for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General Requirements for the Competence of Testing and Calibration Laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated 18 June 2005*).



Presented this 6th day of November 2008.

A handwritten signature in cursive script, appearing to read "Peter Abney".

President

For the Accreditation Council

Certificate Number 2201.01

Valid to September 30, 2010

Revised August 25, 2010

For the tests or types of tests to which this accreditation applies,
please refer to the laboratory's Electrical Scope of Accreditation.

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005²

DELPHI-ELECTRONICS & SAFETY TEST LAB
Mexico Technical Center Laboratory³
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ELECTRICAL (AEMCLAP/EMC)

Valid to: September 30, 2010

Certificate Number: 2201.01

In recognition of the successful completion of the A2LA and the Automotive EMC Laboratory Accreditation Program (AEMCLAP)⁽¹⁾ evaluation process, accreditation is granted to this laboratory to perform the following automotive electromagnetic compatibility tests:

Test Technology

Test Method(s)

*AEMCLRP⁽¹⁾ (Rev. 4) Recognized Tests
and Addendum May 25, 2007*

Electrostatic Discharge (ESD)
Appendix D
(Chrysler, Ford, GM)
Test Set-up Designation:
LAB 1 - ESD Room Bench 1 and Bench 2

ISO 10605 (2001);
DC 11224 (Change A) Sections 10.1, 10.2;
ES-XW7T-1A278-AC (CI 280);
GMW 3097 (2006) Section 3.6

RF Conducted Emissions
Appendix F
(Chrysler, Ford, GM)
Test Set-up Designation:
LAB 1 - Chamber 4

CISPR 25 (2002) Section 6.2;
DC 11224 (Change A) Section 6.2;
ES-XW7T-1A278-AC (CE420);
GMW 3097 (2006) Section 3.3.2

Radiated Emissions
Appendix G
(Chrysler, Ford, GM)
Test Set-up Designation:
LAB 1 - Chamber 4

CISPR 25 (2002) Section 6.4;
DC 11224 (Change A) Section 6.4;
ES-XW7T-1A278-AC (RE 310);
GMW 3097 (2006) Section 3.3.1

Test Technology

*AEMCLRP⁽¹⁾ (Rev. 4) Recognized Tests
and Addendum May 25, 2007*

Test Method(s)

Bulk Current Injection (BCI)
Substitution Method
Appendix I
(Chrysler, Ford, GM)
Test Set-up Designation:
LAB 1 -Chambers 1, 2 and 3

ISO 11452-4 (2005);
DC 11224 (Change A) Section 7.2;
ES-XW7T-1A278-AC (RI 112);
GMW 3097 (2006) Section 3.4.1

Transverse Electromagnetic (TEM) Cell
Appendix J
*(Frequency Range 10 kHz-200 MHz, up to 200
V/m)*
(Chrysler)
Test Set-up Designation:
LAB 1 - Cell 1

ISO 11452-3 (2001),
DC 11224 (Change A) Section 7.5

Absorber-lined Shielded Enclosure (ALSE)
Appendix K
*(200 MHz to 18 GHz, 200 V/m),
(100 V/m 200 – 400 MHz horizontal)*
(Chrysler, Ford, GM)
*(Using Nonmetallic Bench with metallic
surface Ground Plane)*
Test Set-up Designation:
LAB 1 Chamber 4

ISO 11452-2 (2004);
DC 11224 (Change A) Sections 7.3, 7.4;
ES-XW7T-1A278-AC (RI 114);
GMW 3097 (2006) Section 3.4.2

Reverberation Radiated Immunity Mode Tuned
Appendix L
(Ford, GM)
Test Set-up Designation:
EMC LAB 2 - Chamber 5

ISO/IEC 61000-4-21 (2003);
GMW 3097 (2006) Section 3.4.3;
ES-XW7T-1A278-AC (RI 114)

Absorber Lined Shielded Enclosure Radar
Pulse Only
Appendix M
(Ford, GM)
Test Set-up Designation:
Lab 1 Chamber 4
Limited to 300 V/m;

ISO 11452-2;
ES-XW7T-1A278-AC (RI 114);
GMW 3097 (2006) Section 3.4.2

<u>Test Technology</u>	<u>Test Method(s)</u>
<i>Non-AEMCLRP EMC Tests:</i>	
Radiated Emissions	CISPR 25; SAE J1113-41
Bulk Current Injection (BCI) Substitution Method	SAE J1113-4;
Closed Loop	ISO 11452-4; SAE J1113-4,
Absorber-lined Shielded Enclosure (ALSE) (200 MHz to 18 GHz, 200 V/m), (100 V/m 200 – 400 MHz horizontal) Nonmetallic Bench with Metallic Surface	SAE J1113-21
Transverse Electromagnetic (TEM) Cell	SAE J1113-24
Electrostatic Discharge (ESD)	SAE J1113-13
Conducted Transients & Conducted Transient Emissions	ISO 7637-2, ISO 7637-3
Electrical System Performance Requirements (excluding sections 6 and 9)	DC 10615

¹ A2LA provides Accreditation for the Automotive EMC Laboratory Recognition Program (AEMCLRP) which is designated as the Automotive EMC Laboratory Accreditation Program (AEMCLAP). Chrysler, Ford Motor Company (Ford) and General Motors Corporation (GM) provide overall recognition as part of the AEMCLRP document (Fourth Edition, 01/27/06 and the Addendum May 25, 2007). This document is available on the A2LA web site (www.A2LA.org). Accreditation to the A2LA AEMCLAP requirements does not ensure recognition by the aforementioned organizations. Confirmation of recognition can be obtained from these organizations directly.

² Accreditation to ISO/IEC 17025 may be used to demonstrate supplier in-house laboratory conformity to the section 7.6.3.1 laboratory requirement of ISO/TS 16949:2002.

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